

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination HAYNES ET AL.	
			Examiner Eric A. Wiener	Art Unit 2112	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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